

<b>Notice of References Cited</b>	Application/Control No. 09/856,422		Applicant(s)/Patent Under Reexamination KAM, ZVI	
	Examiner Brian P. Werner		Art Unit 2621	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,384,952	05-2002	Clark et al.	359/224
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Farhana Kagalwala et al., Computational model of DIC microscopy for reconstructing 3-D specimens: from observations to measurement, Conference on Three-dimensional and multidimensional microscopy, San Jose CA, 27-29 January, 1998, pp. 35-36.
	V	N. S. White et al., Aberration control in quantitative imaging of botanical specimens by multidimensional fluorescence microscopy, Journal of Microscopy, Vol. 181, Pt. 2, February 1996, pp. 99-116.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.